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U.S. Department of Commerce Patent and Trademark Office

(PTO Form 1449 modified)

Docket No.

AMAT/6120/CPI/ECP/PJS

Serial No.

10/036,321

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant

Stevens, et al.

Confirmation No.:

3220

(Use several sheets if necessary)

Filing Date

12/26/2001

Group

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Examiner Unknown

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							YES	NO
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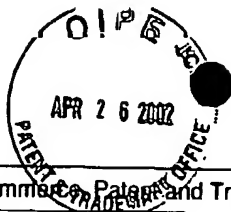
J. G.

Date Considered

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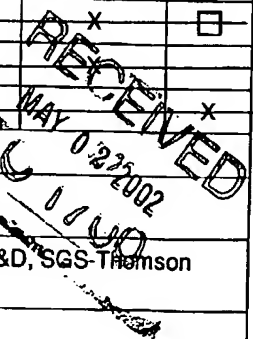
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(Use several sheets if necessary)		Filing Date 12/26/2001	Group 1741 1734
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Sheet 3 of 3 sheet(s)

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant Stevens, et al.	Confirmation No.: 3220
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